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U.S. UTILITY Patent Application
O.I.P.E. PATENT DATE

SCANNED

APPLICATION NO. CONT/PRIOR CLASS	SUBCLASS .	ART UNIT - 3724	EXAMINER!	
VITLE OF INVENTION: Yasuo Fukuda Masakatsu Nagata Shoji Iwasaki Osamu Nakao	81			Phan
APPLEADECTION electrode, it an electronic component	s forming	method and	apparatus	for testing PTO-2040 - 12/99 :

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ORIGINAL			CROSS R	EFERENCE	E(S)		
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TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED			
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.		
☐ The term of this patent				NOTICE OF ALL	OWANCE MAILED		
subsequent to (date) has been disclaimed.	(Assistant Examiner). (Da		(Date)				
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